

Absolute Maximum Ratings (T_A = 25°C Unless Otherwise Noted)

| Symbol | Parameter | Rating | Unit | |
|-------------------------------|---|-----------------------|------------------|------|
| Common Ratings | | | | |
| V _{DSS} | Drain-Source Voltage | 75 | V | |
| V _{GSS} | Gate-Source Voltage | ±25 | | |
| T _J | Maximum Junction Temperature | 150 | °C | |
| T _{STG} | Storage Temperature Range | -55 to 150 | | |
| I _S | Diode Continuous Forward Current | T _C =25°C | 80 | A |
| I _D | Continuous Drain Current(Silicon Limited) | T _C =25°C | 170 ^a | |
| | Continuous Drain Current(Wire Bond Limited) | T _C =25°C | 120 ^a | |
| I _{DM} | Pulsed Drain Current | T _C =25°C | 400 ^b | |
| P _D | Maximum Power Dissipation | T _C =25°C | 250 | W |
| | | T _C =100°C | 100 | |
| R _{θJC} | Thermal Resistance-Junction to Case | Steady State | 0.5 | °C/W |
| I _D | Continuous Drain Current | T _A =25°C | 17 | A |
| | | T _A =70°C | 14 | |
| P _D | Maximum Power Dissipation | T _A =25°C | 2.5 | W |
| | | T _A =70°C | 1.6 | |
| R _{θJA} [*] | Thermal Resistance-Junction to Ambient | Steady State | 50 | °C/W |
| I _{AS} ^c | Avalanche Current, Single pulse | L=0.5mH | 50 | A |
| E _{AS} ^c | Avalanche Energy, Single pulse | L=0.5mH | 620 | mJ |

Note * : Surface Mounted on 1in² pad area.

Note a : Bond wire current limit is 120A.

Note b : Pulse width limited by max. junction temperature.

Note c : UIS tested and pulse width limited by maximum junction temperature 150°C (initial temperature T_J=25°C).

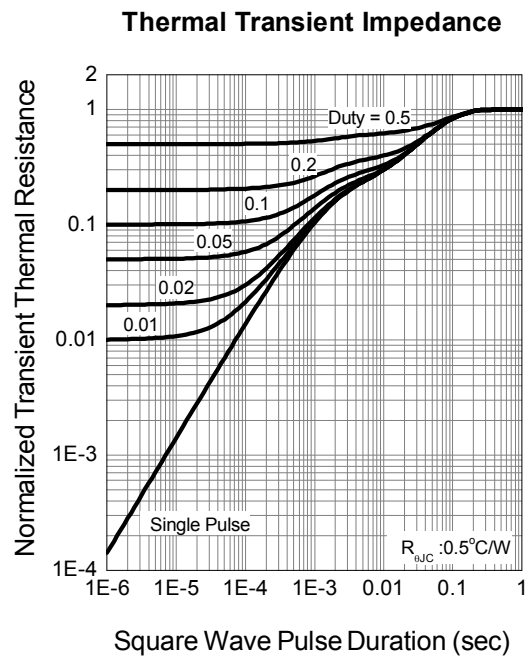
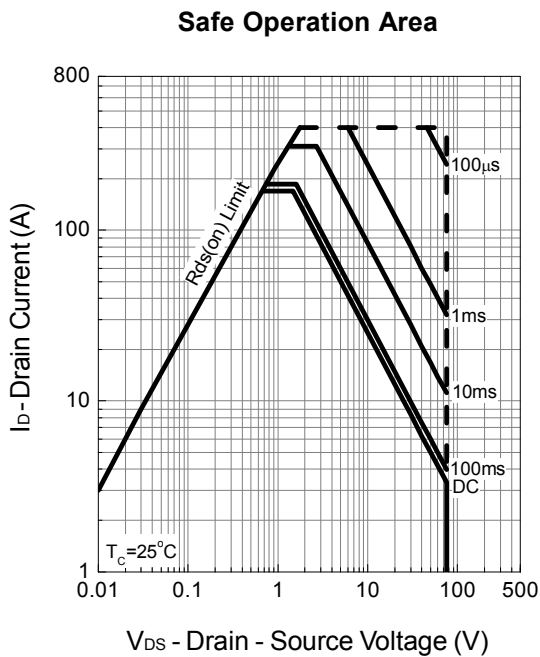
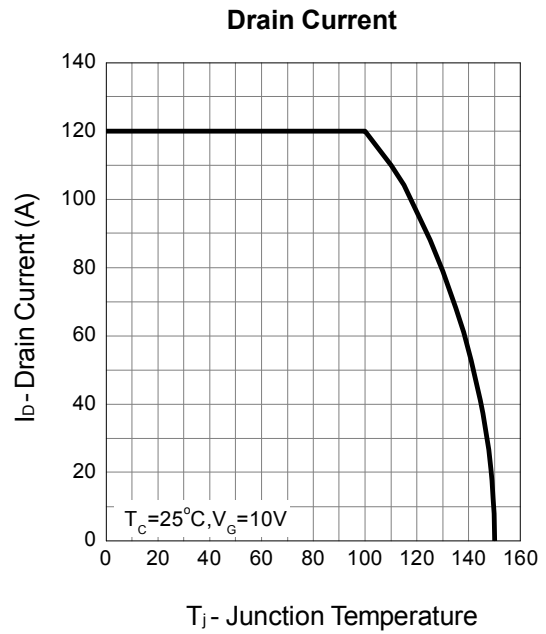
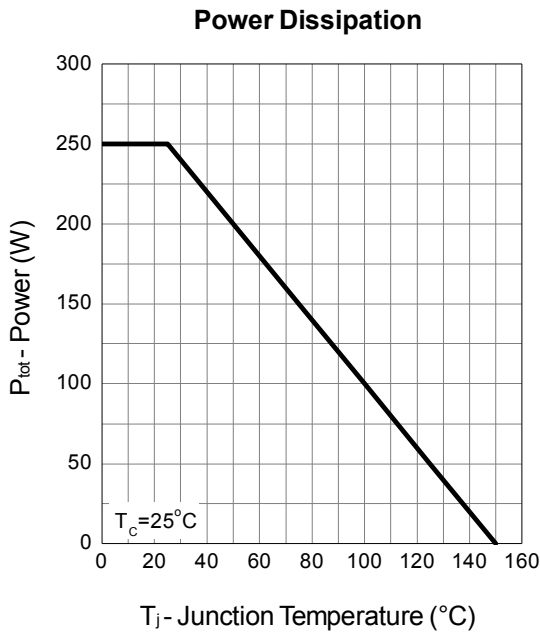
Electrical Characteristics (T_A = 25°C Unless Otherwise Noted)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|--|----------------------------------|---|------|------|------|------|
| Static Characteristics | | | | | | |
| B _{VDS} | Drain-Source Breakdown Voltage | V _{GS} =0V, I _{DS} =250μA | 75 | - | - | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} =60V, V _{GS} =0V | - | - | 1 | μA |
| | | T _J =85°C | - | - | 30 | |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} , I _{DS} =250μA | 2 | 3 | 4 | V |
| I _{GSS} | Gate Leakage Current | V _{GS} =±25V, V _{DS} =0V | - | - | ±100 | nA |
| R _{DS(ON)} ^d | Drain-Source On-state Resistance | V _{GS} =10V, I _{DS} =40A | - | 3.6 | 4.3 | mΩ |
| Diode Characteristics | | | | | | |
| V _{SD} ^d | Diode Forward Voltage | I _{SD} =20A, V _{GS} =0V | - | 0.8 | 1.3 | V |
| t _{rr} | Reverse Recovery Time | I _{SD} =40A, dI _{SD} /dt=100A/μs | - | 52 | - | ns |
| Q _{rr} | Reverse Recovery Charge | | - | 105 | - | nC |
| Dynamic Characteristics^e | | | | | | |
| R _G | Gate Resistance | V _{GS} =0V, V _{DS} =0V, f=1MHz | - | 1.2 | - | Ω |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} =30V, Frequency=1.0MHz | - | 5200 | 6760 | pF |
| C _{oss} | Output Capacitance | | - | 930 | - | |
| C _{rss} | Reverse Transfer Capacitance | | - | 255 | - | |
| t _{d(ON)} | Turn-on Delay Time | V _{DD} =30V, R _L =30Ω, I _{DS} =1A, V _{GEN} =10V, R _G =6Ω | - | 26 | 47 | ns |
| t _r | Turn-on Rise Time | | - | 17 | 31 | |
| t _{d(OFF)} | Turn-off Delay Time | | - | 88 | 156 | |
| t _f | Turn-off Fall Time | | - | 90 | 162 | |
| Gate Charge Characteristics^e | | | | | | |
| Q _g | Total Gate Charge | V _{DS} =30V, V _{GS} =10V, I _{DS} =40A | - | 94 | 132 | nC |
| Q _{gs} | Gate-Source Charge | | - | 27 | - | |
| Q _{gd} | Gate-Drain Charge | | - | 23 | - | |

Note d : Pulse test; pulse width≤300μs, duty cycle≤2%.

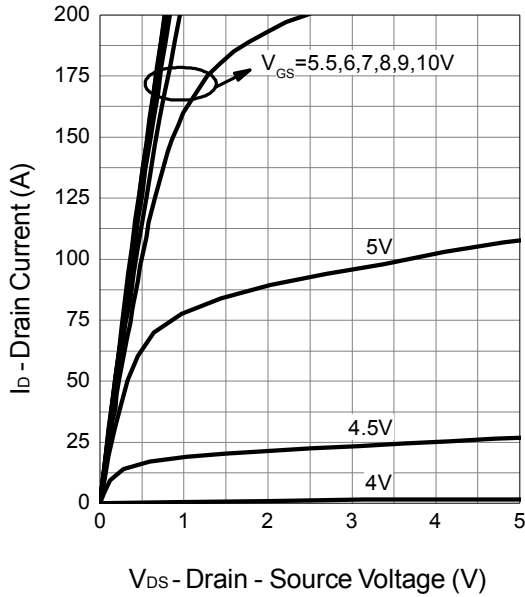
Note e : Guaranteed by design, not subject to production testing.

Typical Operating Characteristics

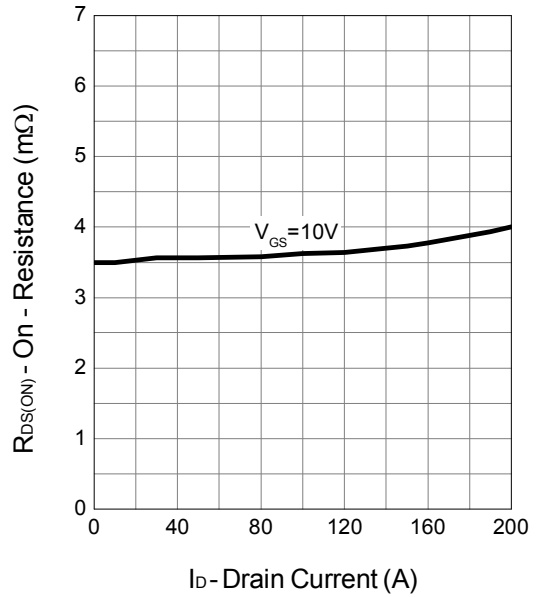


Typical Operating Characteristics (Cont.)

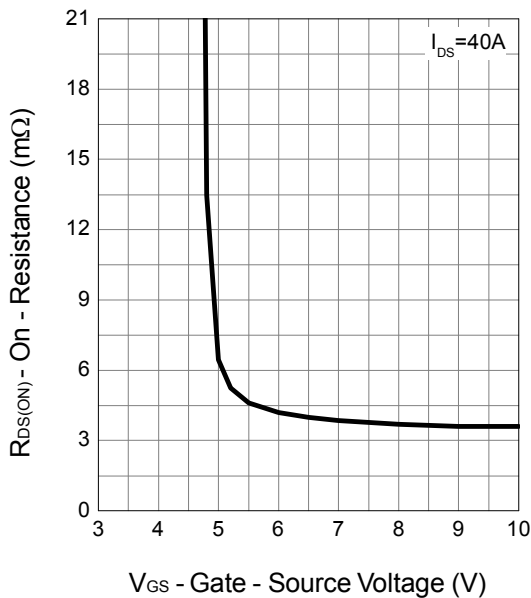
Output Characteristics



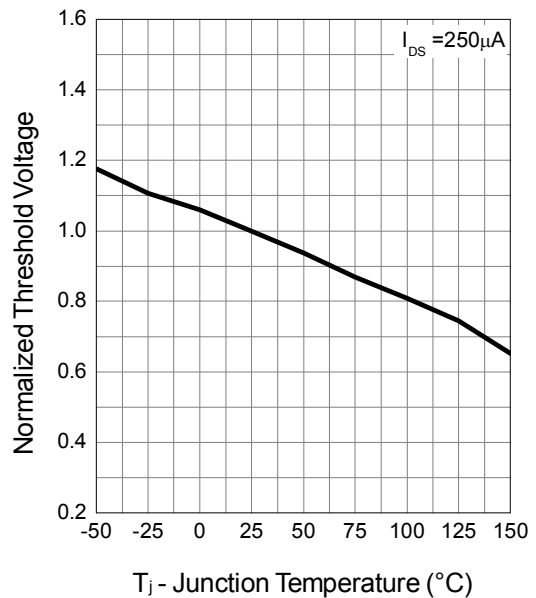
Drain-Source On Resistance



Gate-Source On Resistance

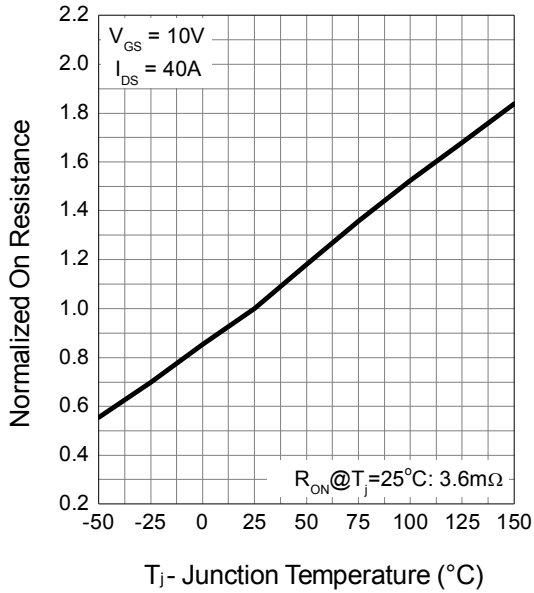


Gate Threshold Voltage

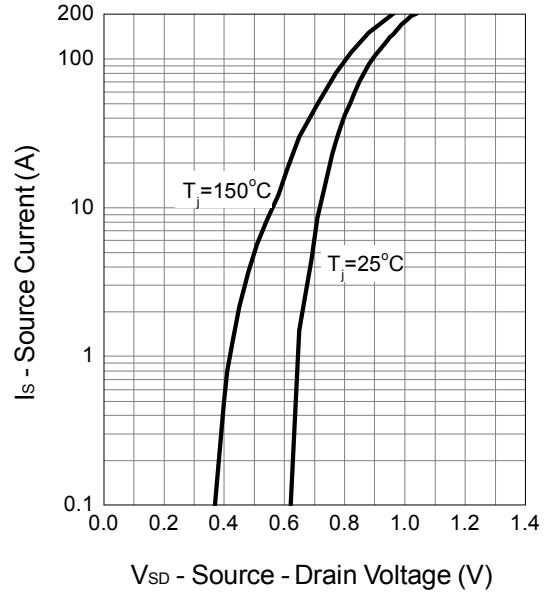


Typical Operating Characteristics (Cont.)

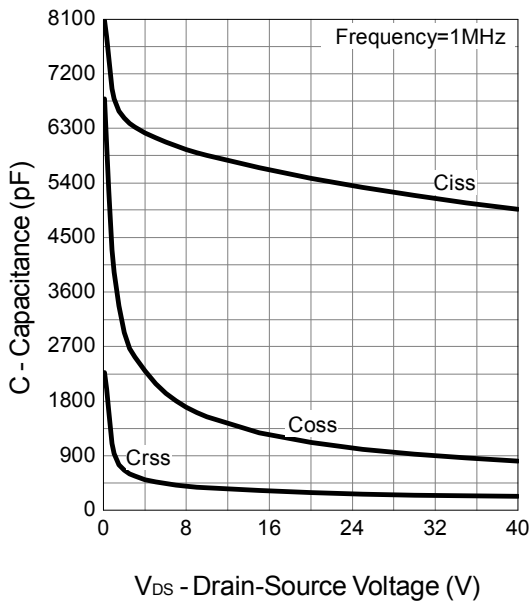
Drain-Source On Resistance



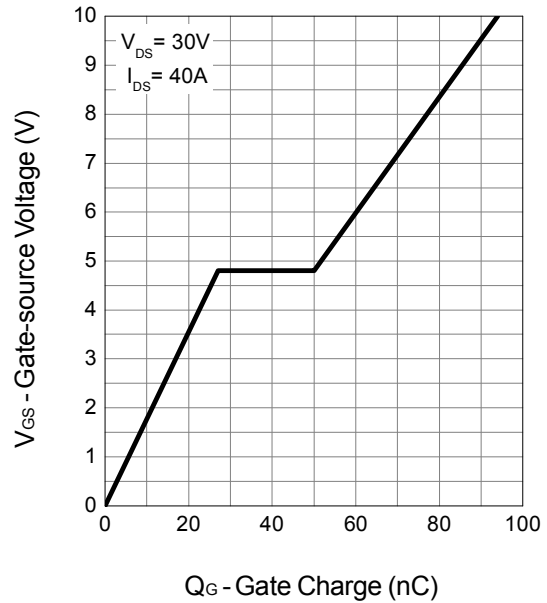
Source-Drain Diode Forward



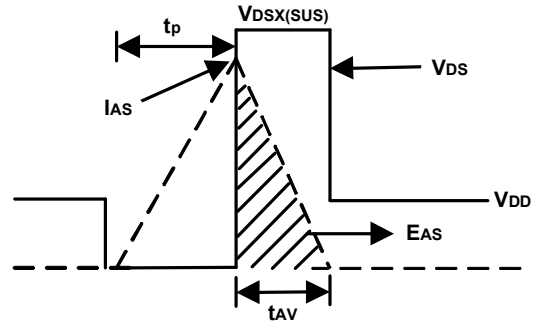
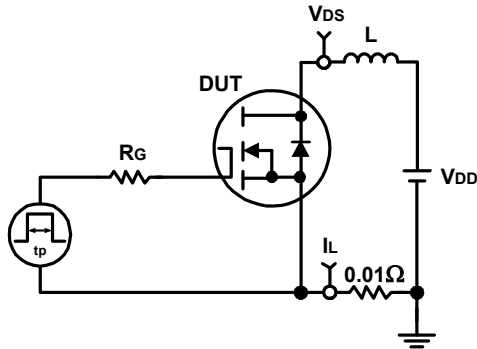
Capacitance



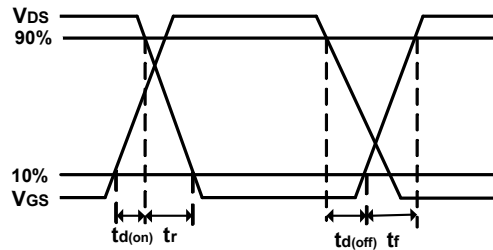
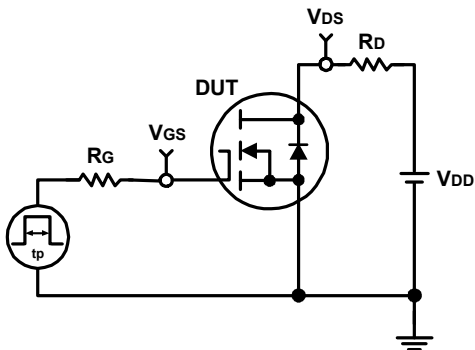
Gate Charge



Avalanche Test Circuit and Waveforms

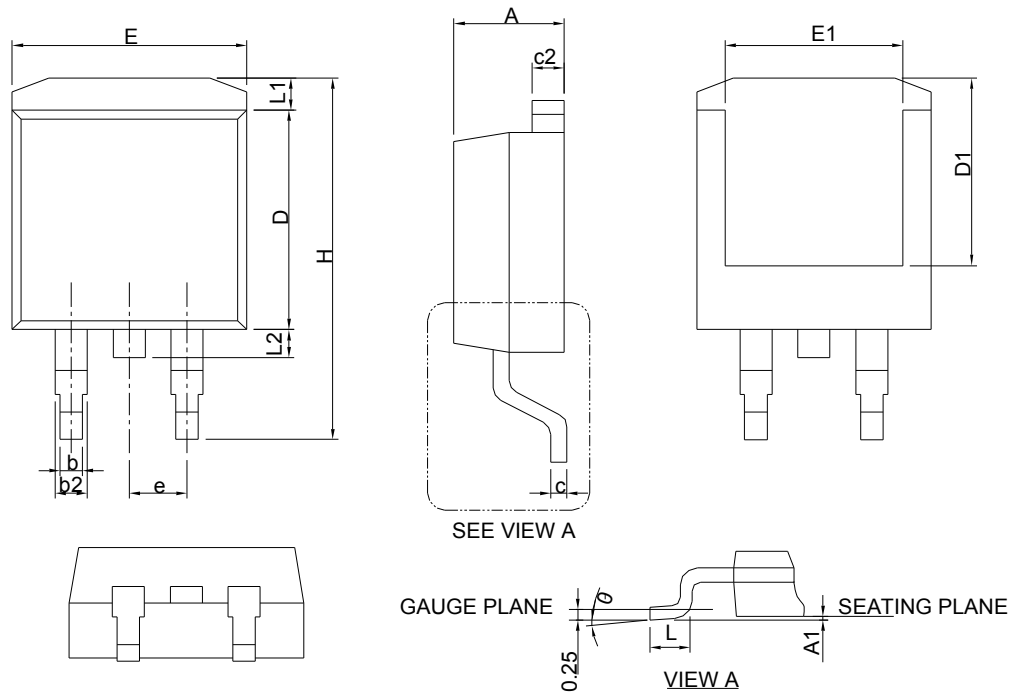


Switching Time Test Circuit and Waveforms



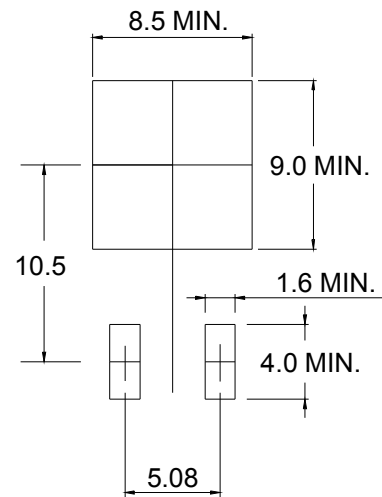
Package Information

TO-263-3



| DIMENSIONS | TO-263-3 | | | |
|------------|-------------|-------|-----------|-------|
| | MILLIMETERS | | INCHES | |
| | MIN. | MAX. | MIN. | MAX. |
| A | 4.06 | 4.83 | 0.160 | 0.190 |
| A1 | 0.00 | 0.25 | 0.000 | 0.010 |
| b | 0.51 | 0.99 | 0.020 | 0.039 |
| b2 | 1.14 | 1.78 | 0.045 | 0.070 |
| c | 0.38 | 0.74 | 0.015 | 0.029 |
| c2 | 1.14 | 1.65 | 0.045 | 0.065 |
| D | 8.38 | 9.65 | 0.330 | 0.380 |
| D1 | 6.00 | 9.00 | 0.236 | 0.354 |
| E | 9.65 | 11.43 | 0.380 | 0.450 |
| E1 | 6.22 | 9.00 | 0.245 | 0.354 |
| e | 2.54 BSC | | 0.100 BSC | |
| H | 14.61 | 15.88 | 0.575 | 0.625 |
| L | 1.78 | 2.79 | 0.070 | 0.110 |
| L1 | - | 1.68 | - | 0.066 |
| L2 | - | 1.78 | - | 0.070 |
| θ | 0° | 8° | 0° | 8° |

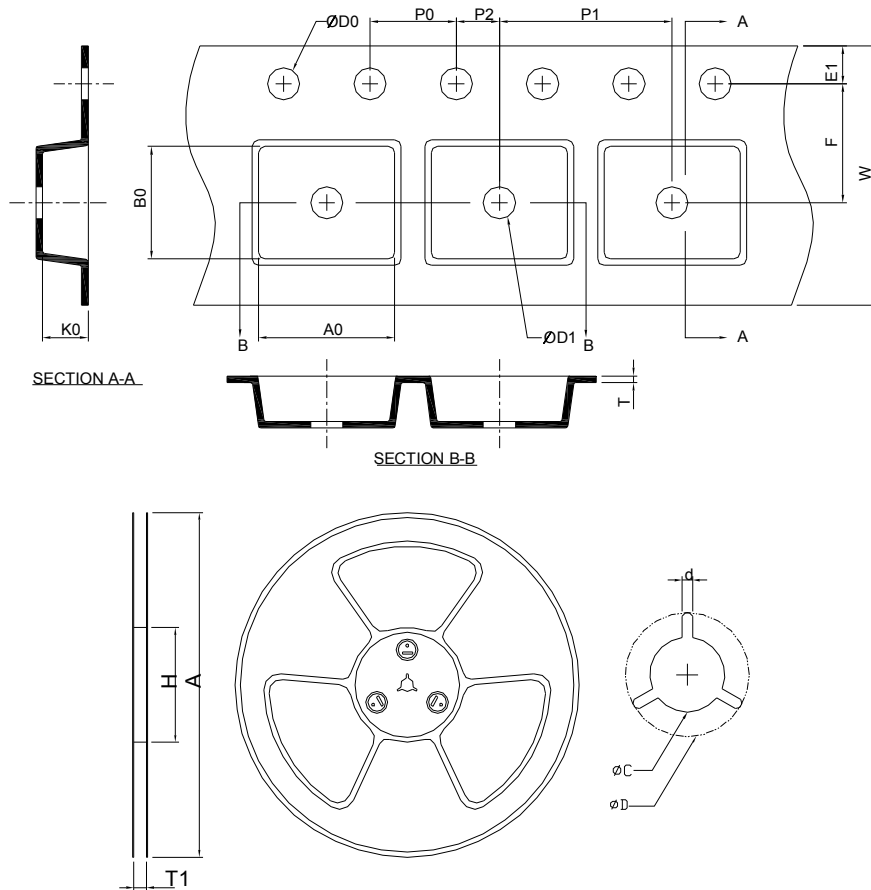
RECOMMENDED LAND PATTERN



UNIT: mm

Note : Follow JEDEC TO-263 AB.

Carrier Tape & Reel Dimensions

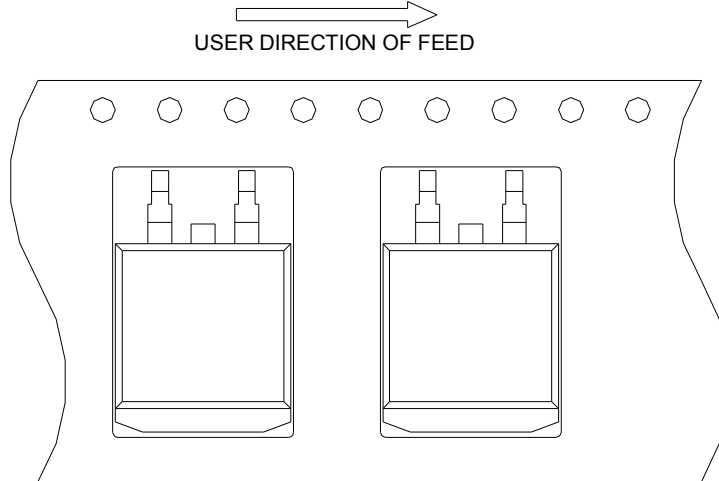


| Application | A | H | T1 | C | d | D | W | E1 | F |
|-------------|------------|-----------|--------------------|--------------------|----------|-------------------|-----------|-----------|-----------|
| TO-263-3 | 330.0±2.00 | 50 MIN. | 24.4+2.00 -0.00 | 13.0+0.50 -0.20 | 1.5 MIN. | 20.2 MIN. | 24.0±0.30 | 1.75±0.10 | 11.5±0.10 |
| | P0 | P1 | P2 | D0 | D1 | T | A0 | B0 | K0 |
| | 4.0±0.10 | 16.0±0.10 | 2.0±0.10 | 1.5+0.10 -0.00 | 1.5 MIN. | 0.6+0.00 -0.40 | 10.8±0.20 | 16.1±0.20 | 5.2±0.20 |

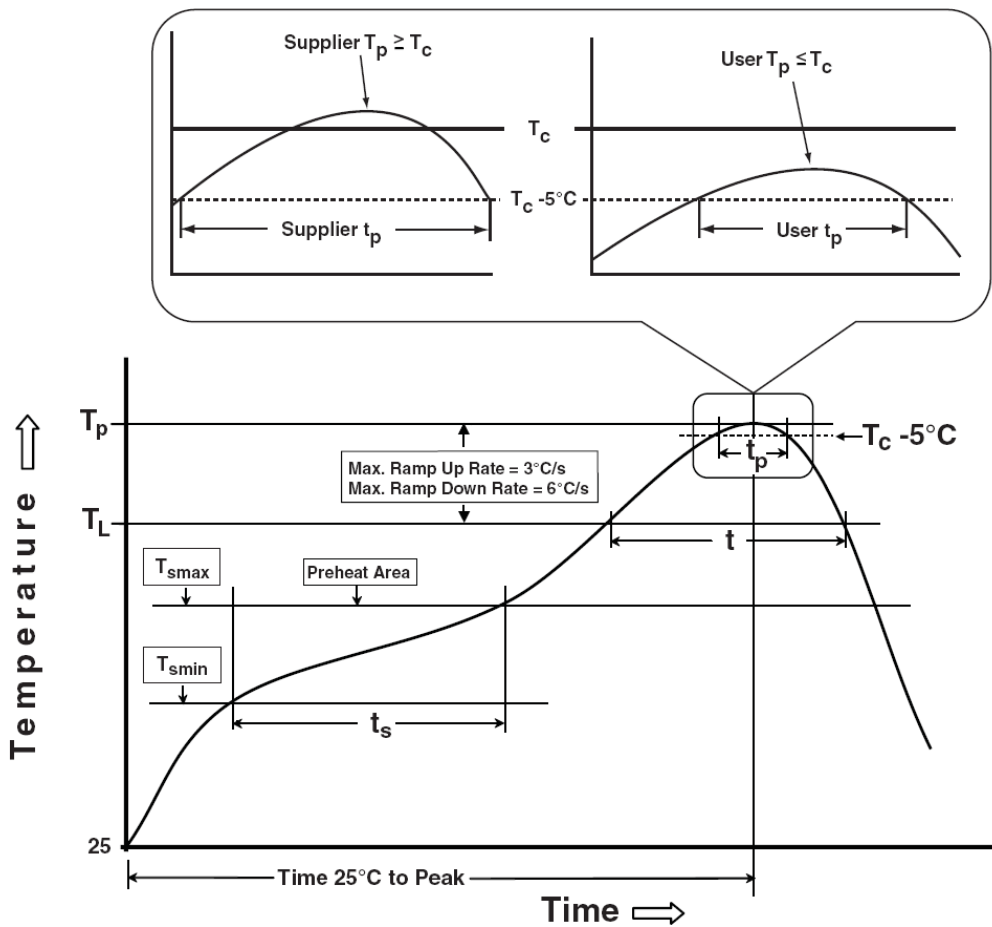
(mm)

Taping Direction Information

TO-263-3



Classification Profile



Classification Reflow Profiles

| Profile Feature | Sn-Pb Eutectic Assembly | Pb-Free Assembly |
|--|------------------------------------|------------------------------------|
| Preheat & Soak | | |
| Temperature min (T_{smin}) | 100 °C | 150 °C |
| Temperature max (T_{smax}) | 150 °C | 200 °C |
| Time (T_{smin} to T_{smax}) (t_s) | 60-120 seconds | 60-120 seconds |
| Average ramp-up rate (T_{smax} to T_p) | 3 °C/second max. | 3°C/second max. |
| Liquidous temperature (T_L) | 183 °C | 217 °C |
| Time at liquidous (t_L) | 60-150 seconds | 60-150 seconds |
| Peak package body Temperature (T_p)* | See Classification Temp in table 1 | See Classification Temp in table 2 |
| Time (t_p)** within 5°C of the specified classification temperature (T_c) | 20** seconds | 30** seconds |
| Average ramp-down rate (T_p to T_{smax}) | 6 °C/second max. | 6 °C/second max. |
| Time 25°C to peak temperature | 6 minutes max. | 8 minutes max. |
| * Tolerance for peak profile Temperature (T_p) is defined as a supplier minimum and a user maximum. | | |
| ** Tolerance for time at peak profile temperature (t_p) is defined as a supplier minimum and a user maximum. | | |

Table 1. SnPb Eutectic Process – Classification Temperatures (T_c)

| Package Thickness | Volume mm ³ <350 | Volume mm ³ ≥350 |
|-------------------|-----------------------------|-----------------------------|
| <2.5 mm | 235 °C | 220 °C |
| ≥2.5 mm | 220 °C | 220 °C |

Table 2. Pb-free Process – Classification Temperatures (T_c)

| Package Thickness | Volume mm ³ <350 | Volume mm ³ 350-2000 | Volume mm ³ >2000 |
|-------------------|-----------------------------|---------------------------------|------------------------------|
| <1.6 mm | 260 °C | 260 °C | 260 °C |
| 1.6 mm – 2.5 mm | 260 °C | 250 °C | 245 °C |
| ≥2.5 mm | 250 °C | 245 °C | 245 °C |

Reliability Test Program

| Test item | Method | Description |
|---------------|---------------|--|
| SOLDERABILITY | JESD-22, B102 | 5 Sec, 245°C |
| HTRB | JESD-22, A108 | 1000 Hrs, 80% of VDS max @ T_{jmax} |
| HTGB | JESD-22, A108 | 1000 Hrs, 100% of VGS max @ T_{jmax} |
| PCT | JESD-22, A102 | 168 Hrs, 100%RH, 2atm, 121°C |
| TCT | JESD-22, A104 | 500 Cycles, -65°C~150°C |

Customer Service

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